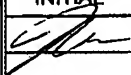
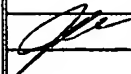
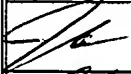
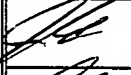


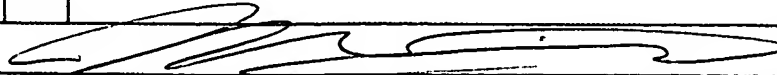
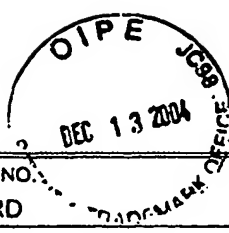


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 243337US2RD		SERIAL NO. New Application		
LIST OF REFERENCES CITED BY APPLICANT					APPLICANT Shigeru HANEDA, et al.				
					FILING DATE Herewith		GROUP		
U.S. PATENT DOCUMENTS									
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE			
	AA	5,416,353	05/16/95	Yuzo KAMIGUCHI, et al.	257	421			
	AB								
	AC								
	AD								
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	AF								
	AG								
	AH								
	AI								
	AJ								
	AK								
	AL								
	AM								
	AN								
FOREIGN PATENT DOCUMENTS									
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION					
				YES	NO				
	AO	11-330387	11/30/99	Japan (with English Abstract)			x		
	AP								
	AQ								
	AR								
	AS								
	AT								
	AU								
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
	AV	N. AKIBA, et al., "Interlayer Exchange in (Ga, Mn) As/ (Al, Ga) As/ (Ga, Mn) As Semiconducting Ferromagnet/Nonmagnet/Ferromagnet Trilayer Structures", APPLIED PHYSICS LETTERS, Vol. 73, No. 15, October 12, 1998, pgs.2122-2124							
	AW	D. CHIBA, et al., "Properties of (Ga, Mn) As/ (Al, Ga) As/ (Ga, Mn) As Magnetic Trilayer Structures", PHYSICA E, Vol. 10, 2001, pgs. 278-282							
	AX	H. OHNO, et al., "Electric-Field Control of Ferromagnetism", NATURE, Vol. 408, December 21/28, 2000, pgs. 944-946							
	AY	D. CHIBA, et al., "Properties of Field-Effect Transistors with a III-V Ferromagnetic Semiconductor Channel Layer", THE 7 TH SYMPOSIUM ON THE PHYSICS AND APPLICATION OF SPIN-RELATED PHENOMENA IN SEMICONDUCTOR, Vol. A7, December 17-18, 2001, pgs. 25-28 (Extended Abstract)							
	AZ					<input type="checkbox"/> Additional References sheet(s) attached			
Examiner 				Date Considered 02/20/2006					
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									



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PATENT AND TRADEMARK OFFICE

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243337US2RD

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10/671,492

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Shigeru HANEDA, et al.

FILING DATE

September 29, 2003

GROUP

2652

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
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	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>ghe</i>	AO	2001-203332	07/27/2001	JAPAN (with English Abstract)		X
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

Date Considered 02/20/2006

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